

-SUPPLEMENTARY INFORMATION-

Experimental corroboration of the thermoelectric performance of Bi₂PdO₄ oxide and Pb- doped derivatives

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Table S1. Unit-cell, atomic positions, thermal parameters and reliability factors for Bi_{1.9}Pb_{0.1}PdO₄ obtained from SXRD data at room temperature, 573, 673 and 773 K.

	298 K	573 K	673 K	773 K
a (Å)	8.62457(6)	8.62397(5)	8.62346(5)	8.62279(4)
c (Å)	5.90929(5)	5.94980(4)	5.96554(4)	5.98211(4)
V (Å ³)	439.551(5)	442.504(5)	443.622(5)	444.785(4)
Bi 8f (x,-x, 1/4)				
x	-0.0799(1)	-0.0793(1)	-0.0792(1)	-0.0788 (1)
Biso	1.05(4)	1.59(4)	1.78(4)	2.12(4)
Pd/Ag 4c (1/4,1/4,z)				
z	0.0832(7)	0.0829(7)	0.0824(7)	0.0832(7)
Biso	0.5 (1)	0.97(9)	1.1 (1)	1.3 (1)
O 16g (x,y,z)				
x	0.472(3)	0.472(2)	0.464(2)	0.465(2)
y	0.133(2)	0.136(2)	0.137(2)	0.139(2)
z	0.089(4)	0.094(3)	0.092(3)	0.089(3)
Biso	2.7(6)	2.3(6)	1.7(5)	1.7(5)
Reliability factors				
R _{Bragg} (%)	11.7	17.1	17.9	18.5
R _p (%)	14.9	13.5	13.9	15.5
R _{wp} (%)	18.7	16.9	17.3	19.4
R _{exp} (%)	14.3	14.1	14.01	13.87
χ ²	1.76	1.44	1.52	1.95

Figure S1. Observed (crosses), calculated (solid line) and difference (bottom) S-XRD Rietveld profiles for Bi_2PdO_4 at (a) 573, (b) 673 and (c) 773 K and $\text{Bi}_{1.90}\text{Pb}_{0.1}\text{PdO}_4$ at (d) 573, (e) 673 and (f) 773 K collected at MSPD diffractometer (ALBA). The vertical green markers represent the positions of the space-group-allowed Bragg reflections





